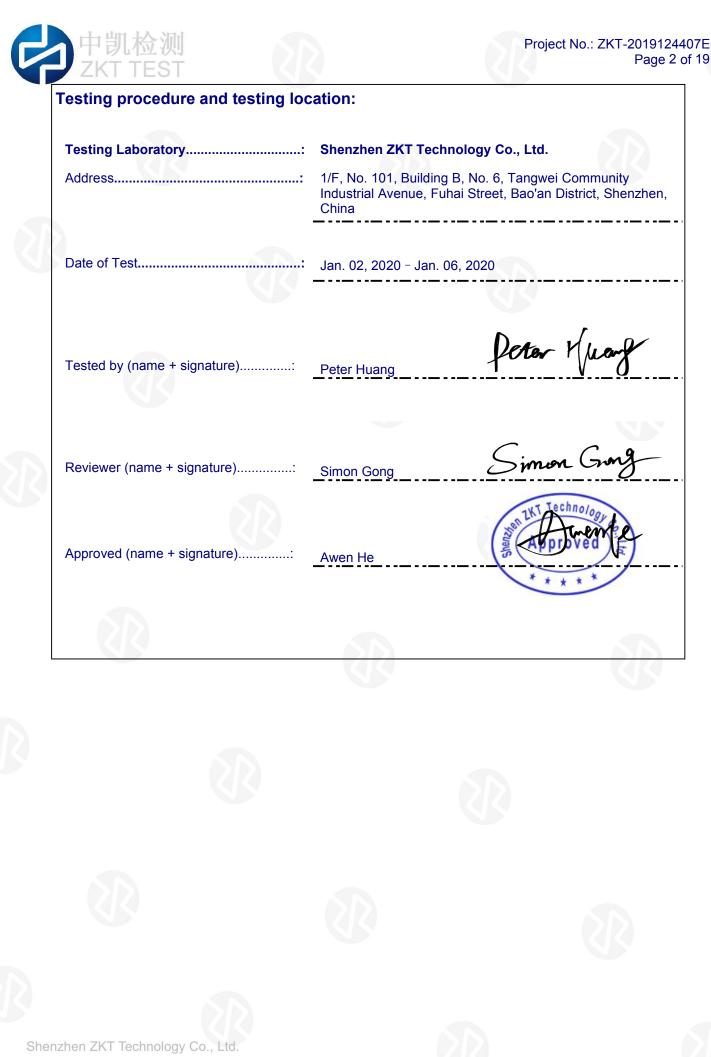


# **EMC TEST REPORT**

Report Reference No:	ZKT-2019124407E
Date of issue	Jan. 06, 2020
Total number of pages	19
Testing Laboratory	Shenzhen ZKT Technology Co., Ltd.
Address:	1/F, No. 101, Building B, No. 6, Tangwei Community Industrial Avenue, Fuhai Street, Bao'an District, Shenzhen, China
Applicant's name:	
Address:	
Test specification:	
Standards	EN 55032:2015
	EN 61000-3-2:2014, EN 61000-3-3:2013
	EN 55035:2017
Test procedure:	N/A
Non-standard test method	N/A
Test Report Form No	-
Test Report Form(s) Originator:	ZKT Testing
Master TRF	Dated: 2017-06
This test report is specially limited to be duplicated without prior written of	to the above client company and product model only. It may no consent of ZKT Test.
Test item description	Power Bank
Trade Mark	N/A
Manufacturer	JMTek Industries(Shenzhen) co., Ltd
Address:	14G, Innovation Tech Building, Quanzhi Science and Technology innovation Park, ShaJing Street, Bao'an District, ShenZhen, China
Model/Type reference:	PB30









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#### **GENERAL INFORMATION** 1.

1.1 Description of Device (EUT)

Booonpaon of Both	
EUT	Power Bank
Model Number	PB30
Model Difference The highest frequency of the internal sources of the EUT is (less than 108)MHz:	<ul> <li>up to 1 GHz.</li> <li>between 108 MHz and 500 MHz, the measurement shall only be made up to 2 GHz.</li> <li>between 500 MHz and 1 GHz, the measurement shall</li> </ul>
	<ul> <li>only be made up to 5 GHz.</li> <li>above 1 GHz, the measurement shall be made up to 5 times the highest frequency or 6 GHz, whichever is less.</li> </ul>
Tested System De	tails

### 1.2

None.

#### **Test Uncertainty** 1.3

**Conducted Emission** Uncertainty

: ±1.82 dB

Radiated Emission Uncertainty: ±2.51 dB

#### **Test Facility** 1.4

Site Description

Name of Firm

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## 2. TEST SUMMARY

The Product has been tested according to the following specifications:

EMISSION				
Standard	Test Item	Test		
EN 55032	Conducted emissions from the AC mains power ports	N/A <sup>5</sup>		
EN 55032	Asymmetric mode conducted emissions	N/A <sup>1</sup>		
EN 55032	Conducted differential voltage emissions	N/A <sup>2</sup>		
EN 55032	Radiated emissions	Yes		
EN 61000-3-2	Harmonic current emission(H)	N/A <sup>5</sup>		
EN 61000-3-3	Voltage fluctuations & flicker(F)	N/A <sup>5</sup>		

IMMUNITY (EN 55035)				
Standard	Test Item	Test		
IEC 61000-4-2	Electrostatic discharge (ESD)	Yes		
IEC 61000-4-3	Continuous RF electromagnetic field disturbances(RS)	Yes		
IEC 61000-4-4	Electrical fast transients/burst (EFT)	N/A <sup>5</sup>		
IEC 61000-4-5	Surges	N/A <sup>5</sup>		
IEC 61000-4-6	Continuous induced RF disturbances (CS)	N/A <sup>5</sup>		
IEC 61000-4-6	Broadband impulse noise disturbances, repetitive	N/A <sup>3</sup>		
IEC 61000-4-6	Broadband impulse noise disturbances, isolated	N/A <sup>3</sup>		
IEC 61000-4-8	Power frequency magnetic field (PFMF)	N/A <sup>4</sup>		
IEC 61000-4-11	Voltage dips and interruptions (DIPS)	N/A <sup>5</sup>		

Remark:

PRODUCTIP REDACTION TOOL ON

- 1. Applicable to ports listed above and intended to connect to cables longer than 3 m.
- 2. The Product has no antenna port.
- 3. Applicable only to CPE xDSL ports.
- 4. The Product doesn't contain any device susceptible to magnetic fields.
- 5. The EUT is powered by the DC only.

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# 3. TEST INSTRUMENT USED

Radiated emissions Test (966 chamber)								
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.			
966 chamber	ChengYu	966 Room	966	Aug. 25, 2019	Aug. 24, 2020			
Receiver	R&S	ESRP	101154	Aug. 14, 2019	Aug. 13, 2020			
Amplifier	Schwarzbeck	BBV9718	9718-309	Aug. 14, 2019	Aug. 13, 2020			
Amplifier	Schwarzbeck	BBV9744	9744-003 7	Aug. 14, 2019	Aug. 13, 2020			
TRILOG Broadband Antenna	schwarzbeck	VULB 9163	VULB916 3-942	Aug. 13, 2019	Aug. 12, 2020			
Horn Antenna	SCHWARZBE CK	BBHA9120 D	1201	Aug. 16, 2019	Aug. 15, 2020			

Electrostatic discharge Test								
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.			
ESD Tester	3C TEST	EDS 30V	ES01216 14	Aug. 16, 2019	Aug. 15, 2020			

Continuous RF electromagnetic field disturbances Test (SMQ site )							
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.		
Signal Generator	HP	8648A	3625U00 573	Sep. 26, 2019	Sep. 26, 2020		
Amplifier	A&R	500A100	17034	Sep. 26, 2019	Sep. 26, 2020		
Amplifier	A&R	100W/1000 M1	17028	Sep. 26, 2019	Sep. 26, 2020		
Audio Analyzer (20Hz~1GH z)	Panasonic	2023B	202301/4 28	Sep. 26, 2019	Sep. 26, 2020		
Isotropic Field Probe	A&R	FP2000	16755	Sep. 26, 2019	Sep. 26, 2020		
Antenna	EMCO	3108	9507-253 4	Sep. 26, 2019	Sep. 26, 2020		
Log-periodi c Antenna	A&R	AT1080	16812	Sep. 26, 2019	Sep. 26, 2020		

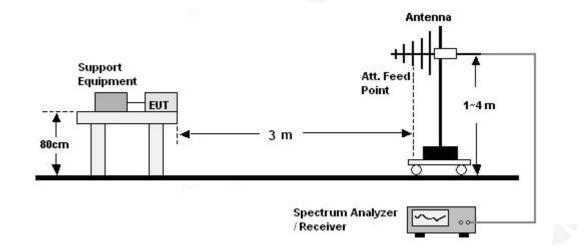
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## 4. RADIATED EMISSIONS TEST

4.1 Block Diagram Of Test Setup

30MHz ~ 1GHz:



### 4.2 Limits

### Limits for radiated disturbance of Class B MME

Frequency (MHz)	Quasi-peak limits at 3m dB(µV/m)				
30-230	40				
230-1000	47				

### 4.3 Test Procedure

### 30MHz ~ 1GHz:

a. The Product was placed on the nonconductive turntable 0.8 m above the ground at a chamber.

b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.

c. For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

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4.4	Test Results	

Radiated Emissions Test Data								
Temperature:26°CRelative Humidity:54%								
Pressure:	1009hPa	Phase :	Horizontal					
Test Voltage :	DC 5V	Test Mode:	Charging					



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1		53.6931	30.96	-14.56	16.40	40.00	-23.60	QP			
2		78.1389	41.13	-19.24	21.89	40.00	-18.11	QP			
3	*	111.3468	52.00	-15.97	36.03	40.00	-3.97	QP			
4	4	156.4578	46.81	-19.04	27.77	40.00	-12.23	QP			
5	8	268.4853	46.82	-14.94	31.88	47.00	-15.12	QP			
6	1	362.9844	38.20	-12.18	26.02	47.00	-20.98	QP			

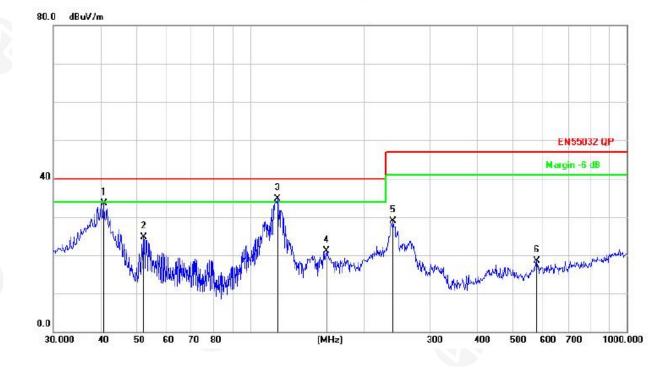
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Radiated Emissions Test Data								
Temperature:	<b>26</b> ℃	Relative Humidity:	54%					
Pressure:	1009hPa	Phase :	Vertical					
Test Voltage :	DC 5V	Test Mode:	Charging					



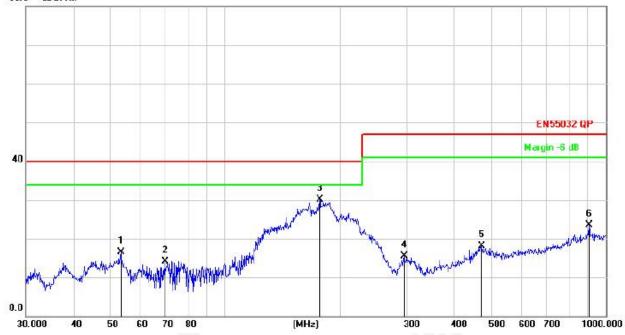
No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1	1	40.8446	48.10	- <mark>14.6</mark> 1	33,49	40.00	-6.51	QP			
2		52.2079	39.05	-14.32	24.73	40.00	-15.27	QP			
3	*	118.1862	51.84	-17.14	34.70	40.00	-5.30	QP			
4		159.7844	40.18	-19.08	21.10	40.00	- <mark>1</mark> 8.90	QP			
5		239.9874	44.36	-15.52	28.84	47.00	-18.16	QP			
6		576.6443	25.61	-7.05	18.56	47.00	-28.44	QP			

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Radiated Emissions Test Data								
Temperature:	<b>26</b> ℃	Relative Humidity:	54%					
Pressure:	1009hPa	Phase :	Horizontal					
Test Voltage :	DC 3.7V	Test Mode:	Discharge					

80.0 dBuV/m

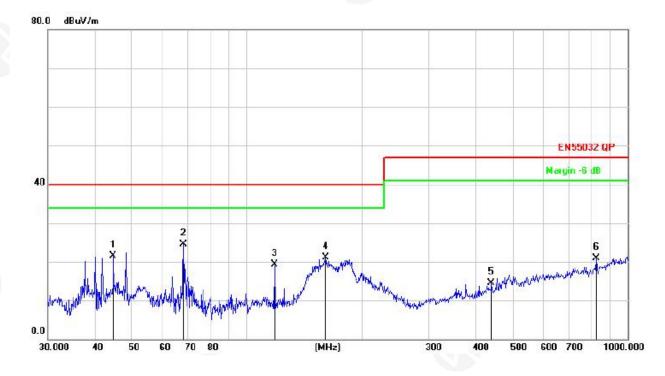


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1		53.3179	30.92	-14.49	16.43	40.00	-23.57	QP			
2		69.6005	31.60	-17.51	14.09	40.00	-25.91	QP			
3	*	177.5092	48.35	-18.20	30.15	40.00	-9.85	QP			
4		295.1469	29.27	-13.72	15.55	47.00	-31.45	QP			
5		472.1760	28.69	-10.55	18.14	47.00	-28.86	QP			
6	1	903.3094	25.75	-2.28	23.47	47.00	-23.53	QP			

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Radiated Emissions Test Data								
Temperature:	<b>26</b> ℃	Relative Humidity:	54%					
Pressure:	1009hPa	Phase :	Vertical					
Test Voltage :	DC 3.7V	Test Mode:	Discharge					



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV/m	dB/m	dB	Detector	cm	degree	Comment
1		44.5868	35.57	-14.10	21.47	40.00	-18.53	QP			
2	*	68.1514	41.76	-17.22	24.54	40.00	-15.46	QP			
3		118.1862	36.41	-17.14	19.27	40.00	-20.73	QP			
4		160.9089	40.10	-19.03	21.07	40.00	-18.93	QP			
5	(7	438.6554	25.29	-10.76	14.53	47.00	-32.47	QP			
6	3	827.4934	24.56	-3.58	20.98	47.00	-26.02	QP			

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## 5. IMMUNITY TEST OF GENERAL THE PERFORMANCE CRITERIA

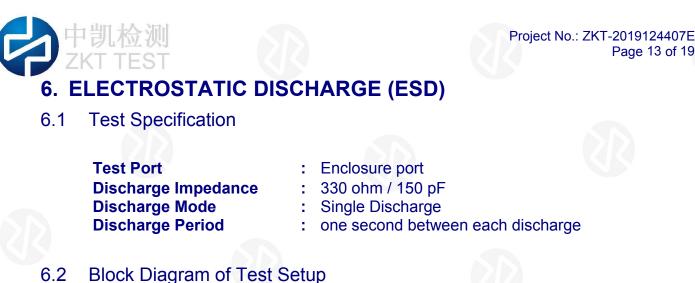
检测 TEST

Product Standard	EN 55035:2017 clause 5
CRITERION A	The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
	During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.
CRITERION B	After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.
	If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
CRITERION C	Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer' s instructions. A reboot or re-start operation is allowed.
	Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

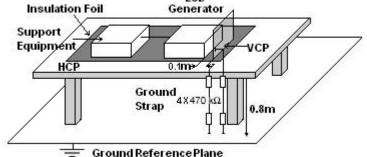
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# ESD Insulation Foil Genera



### 6.3 Test Procedure

a. Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.

b. The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.

c. The time interval between two successive single discharges was at least 1 second.

d. The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.

e. Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.

f. Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.

g. At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the Product were completely illuminated. The VCP (dimensions 0.5m x 0.5m) was placed vertically to and 0.1 meters from the Product.

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Electrostatic Discharge Test Data								
Temperature:	<b>25.1</b> ℃	Humidity:	55%					
Power Supply : DC 5V		Test Mode:	Charging + Discharge					

Discharg e Method	Discharge Position	Voltage (±kV)	Min. No. of Discharge per polarity (Each Point)	Required Level	Performance Criterion
	Conductive Surfaces	2, 4	25	В	А
Contact Discharge	Indirect Discharge HCP	2, 4	25	В	А
	Indirect Discharge VCP	2, 4	25	В	A
Air Discharge	Slots, Apertures, and Insulating Surfaces	2, 4, 8	10	В	А
Note: N/A					

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# 7. CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES(RS)

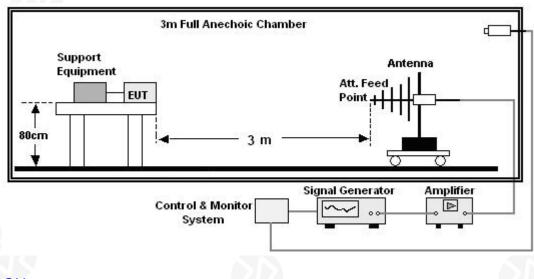
### 7.1 Test Specification

Test Port Step Size Modulation Dwell Time Polarization

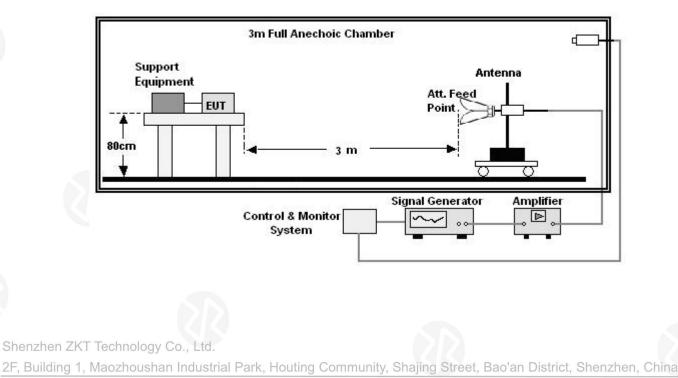
- Enclosure port
- : 1% 1/17 200
- : 1kHz, 80% AM
- 1 second
- : Horizontal & Vertical

### 7.2 Block Diagram of Test Setup

#### Below 1GHz:



#### Above 1GHz:



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a. The testing was performed in a fully-anechoic chamber. The transmit antenna was located at a distance of 3 meters from the Product.

b. The frequency range is swept from 80MHz to 1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz,with the signal 80% amplitude modulated with a 1 kHz sine wave,and the step size was 1%.

c. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond, but should not exceed 5 s at each of the frequencies during the scan.

d. The test was performed with the Product exposed to both vertically and horizontally polarized fields on each of the four sides.

e. For Broadcast reception function: Group 2 not apply in this test.

### 7.4 Test Results

Radio Frequency Electromagnetic Fields Test Data									
Temperature:	<b>25.1℃</b>		Humidity:		Ę	55%			
Power Supply :	DC 5V		Test Mo	de:	Charging	+ Discharge			
Frequency	Position	Str	Field rength Red V/m)		quired Level	Performance Criterion			
80 - 1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz	Front, Right, Back, Left	3		A		A			
Note: N/A		•							

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### EUT Photo 2



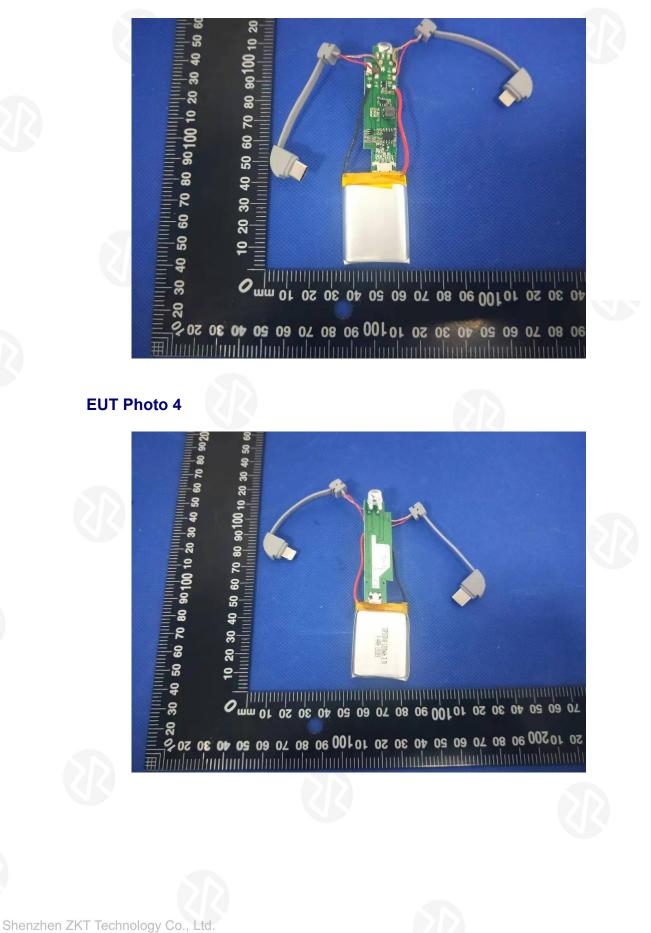
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### EUT Photo 3





# 9. EUT TEST PHOTOGRAPHS





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